

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L6	25444	(reference with voltage) and (latch (flip with flop)) and comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:58
L7	6978	(reference with voltage) same (latch (flip with flop)) same comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:55
L8	2393	(reference with voltage) with (latch (flip with flop)) with comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:55
L9	16977	(reference with voltage) and (flip with flop) and comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:56
L10	4463	(reference with voltage) same (flip with flop) same comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:06
L11	1475	(reference with voltage) with (flip with flop) with comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:14
L12	2	(reference with voltage) with (flip with flop) with comparator with (decouple decoupling decoupler)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:57
L13	18551	(reference adj voltage) and (latch (flip with flop)) and comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 12:59

L14	5440	(reference adj voltage) same (latch (flip with flop) flipflop) same comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:00
L15	1847	(reference adj voltage) with (latch (flip with flop) flipflop) with comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:01
L16	3	(reference adj voltage) with (latch (flip with flop) flipflop) with comparator with (decouple decoupling decoupler decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:03
L26	3091	((test testing) with (chip circuit ic dut)) and (reference) and cell and comparator and (latch flipflop (flip adj flop))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:54
L27	398	((test testing) with (chip circuit ic dut)) and (reference) and cell and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:28
L28	23	((test testing) with (chip circuit ic dut)) and (reference) and (cell same comparator same (latch flipflop (flip adj flop))) and (decouple decoupling decoupler)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:29
L29	1188	((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and cell and comparator and (latch flipflop (flip adj flop))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:35
L30	421	((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:36

L31	392	((test testing) with (chip circuit ic dut)) and (reference adj (voltage input)) and ((test supply) with voltage) and comparator and (latch flipflop (flip adj flop)) and (decouple decoupling decoupler decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:38
L32	5	((test testing) with (chip circuit ic dut)) and ((reference adj (voltage input)) same ((test supply) with voltage) same comparator same (latch flipflop (flip adj flop))) and (decouple decoupling decoupler decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:47
L34	20639	(comparator with ((flip with flop) flipflop))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:48
L35	4630	comparator same ((flip with flop) flipflop) same (reference with voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:52
L36	15	comparator same ((flip with flop) flipflop) same (reference with voltage) same (decoupling decouple decoupler decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:49
L37	4149	comparator same output same ((flip with flop) flipflop) same (reference with voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:53
L38	1015	comparator with output with ((flip with flop) flipflop) with (reference with voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:54
L39	1	((test testing) with (chip circuit ic dut)) and (comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (decoupling decoupler decouple decoupled)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 13:57

L40	39	((test testing) with (chip circuit ic dut)) and (comparator with output with ((flip with flop) flipflop) with (reference with voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:38
L41	1	((test testing) with (chip circuit ic dut)) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under with voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over with voltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:41
L42	5	((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under with voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over with voltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:45
L43	0	((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage) (under adj voltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage) (over adj voltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:42
L44	0	((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((undervoltage))) and ((comparator with output with ((flip with flop) flipflop) with (reference with voltage)) same ((overvoltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:46
L45	22	(comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (comparator same ((undervoltage) (under with voltage))) and (comparator same ((overvoltage) (over with voltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 15:03

L46	2	(comparator with output with ((flip with flop) flipflop) with (reference with voltage)) and (comparator same ((undervoltage))) and (comparator same ((overvoltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 14:50
L47	161	(Ernest with Allen) (David with Castaneda)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 15:04
L48	1	47 and ((flipflop) latch (flip with flop)) and comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/14 15:06

10700790_LIST

10700790

PLUS Search Results for S/N 10700790, Searched February 14, 2005

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

5792944
5886252
5889837
5513062
5631537
6118293
6301133
6744242
4803592
5886429
4333119
4559497
4860185
4999730
4400624
4475047
4825328
4847720
4980791
5224010
5577890
5641587
5652501
5717937
5831350
5861812
6011358
6060864
6693781
5402119
6112322
6049445
6314011
6324088
6400595
6452825
6477073
4457404
5218196
5559664
6094033
6229285
5023545
5351519
5519331
5552744
5694063
6043672
5795039
5335024